

# CE EMC TEST REPORT

Report No.: DDT-B22081804-1E01

<b>Applicant</b>	:	TPV Electronics (Fujian) Co., Ltd.
<b>Address</b>	:	Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
<b>Equipment under Test</b>	:	LCD Monitor
<b>Model No.</b>	:	**32G3*****,U32G3**** ("*" = 0-9, A-Z, a-z, +, -, /, \ or blank)
<b>Trade Mark</b>	:	N/A

**Issued By:** Tianjin Dongdian Testing Service Co., Ltd.

**Address:** Building D-1, No. 19, Weishi Road, Microelectronics Industrial Park, Development Area, Tianjin, China.

**Tel:** +86-22-58038033, **E-mail:** dot@dddt.com, <http://www.ddttest.com>



# REPORT

## CONTENTS

1.	Summary of Test Results .....	7
2.	General Test Information .....	8
2.1	Description of EUT .....	8
2.2	Primary Function of EUT .....	8
2.3	Port of EUT .....	9
2.4	Accessories of EUT .....	9
2.5	Test peripherals .....	9
2.6	Block diagram EUT configuration for test .....	10
2.7	EUT operating mode(s) .....	10
2.8	Performance Criteria .....	11
2.9	Deviations of test standard .....	11
2.10	Test laboratory .....	12
2.11	Measurement uncertainty .....	12
3.	Conducted Emission (mains power port) .....	13
3.1	General information .....	13
3.2	Test Equipment .....	13
3.3	Reference standard .....	13
3.4	Block diagram of test setup .....	13
3.5	Limits .....	14
3.6	Test procedure .....	14
3.7	Test result .....	16
4.	Conducted Emission (Telecommunication Port) .....	17
4.1	General information .....	17
4.2	Test equipment .....	17
4.3	Reference standard .....	17
4.4	Block diagram of test setup .....	17
4.5	Limits for conducted disturbance at the telecommunication ports .....	18
4.6	Test procedure .....	18
4.7	Test result .....	18
5.	Radiated Emissions (30MHz to 1GHz) .....	19
5.1	General information .....	19
5.2	Test equipment .....	19
5.3	Reference standard .....	19
5.4	Block diagram of test setup .....	20
5.5	Limits .....	20
5.6	Test procedure .....	21
5.7	Test result .....	23
6.	Radiated Emissions (Above 1GHz) .....	24
6.1	General information .....	24
6.2	Test equipment .....	24
6.3	Reference standard .....	24
6.4	Block diagram of test setup .....	25
6.5	Limits .....	25
6.6	Test procedure .....	25
6.7	Test result .....	27
7.	Harmonics current .....	28
7.1	General information .....	28
7.2	Test equipment .....	28
7.3	Reference standard .....	28
7.4	Block diagram of test setup .....	28
7.5	Limits .....	29
7.6	Test result .....	29
8.	Voltage fluctuation & Flicker .....	31
8.1	General information .....	31
8.2	Test equipment .....	31
8.3	Reference standard .....	31
8.4	Block diagram of test setup .....	32

8.5	Limits.....	32
8.6	Test result .....	32
9.	Electrostatic Discharge .....	34
9.1	General information .....	34
9.2	Test equipment .....	34
9.3	Test and reference standards.....	34
9.4	Block diagram of test setup .....	34
9.5	Test levels and performance criterion .....	35
9.6	Test procedure.....	35
9.7	Test result .....	36
10.	Continuous Radio Frequency Disturbances.....	38
10.1	General information .....	38
10.2	Test equipment .....	38
10.3	Test and reference standards.....	38
10.4	Block diagram of test setup .....	38
10.5	Test levels and performance criterion .....	39
10.6	Test procedure.....	40
10.7	Test result .....	40
11.	Electrical Fast Transients (EFT).....	41
11.1	General information .....	41
11.2	Test equipment .....	41
11.3	Test and reference standards.....	41
11.4	Block diagram of test setup .....	41
11.5	Test levels and performance criterion .....	42
11.6	Test Procedure .....	42
11.7	Test result .....	43
12.	Surges.....	44
12.1	General information .....	44
12.2	Test equipment .....	44
12.3	Test and reference standards.....	44
12.4	Block diagram of test setup .....	44
12.5	Test levels and performance criterion .....	45
12.6	Test Procedure .....	45
12.7	Test result .....	46
13.	Continuous Conducted Disturbances.....	47
13.1	General information .....	47
13.2	Test Equipment.....	47
13.3	Test and reference standards.....	47
13.4	Block diagram of test setup .....	47
13.5	Test levels and performance criterion .....	48
13.6	Test procedure.....	49
13.7	Test result .....	49
14.	Power-Frequency Magnetic Fields.....	50
14.1	General information .....	50
14.2	Test equipment .....	50
14.3	Test and reference standards.....	50
14.4	Block diagram of test setup .....	50
14.5	Test levels and performance criterion .....	51
14.6	Test procedure.....	51
14.7	Test result .....	51
15.	Voltage Dips and Interruptions .....	52
15.1	General information .....	52
15.2	Test equipment .....	52
15.3	Test and reference standards.....	52
15.4	Block diagram of test setup .....	52
15.5	Test levels and performance criterion .....	52
15.6	Test procedure.....	53
15.7	Test result .....	53

Annex A Test Setup Photos ..... 54

## Test Report Declare

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### Test Standard Used:

EN 55032:2015, EN 55032:2015/A11:2020, EN 55032:2015/A1:2020,  
CISPR 32:2015/AMD1:2019, AS/NZS CISPR 32:2015 AMD 1:2020  
BS EN 55032:2015, BS EN 55032:2015+A11:2020, BS EN 55032:2015+A1:2020  
EN 55035:2017, EN 55035:2017/A11:2020, CISPR 35:2016, BS EN 55035:2017  
BS EN 55035:2017+A11:2020  
EN 61000-3-2:2014, EN IEC 61000-3-2:2019/A1:2021, BS EN 61000-3-2:2014, BS EN IEC  
61000-3-2:2019+A1:2021  
EN 61000-3-3:2013, EN 61000-3-3:2013/A1:2019, EN 61000-3-3:2013/A2:2021, BS EN 61000-3-  
3:2013, BS EN 61000-3-3:2013+A1:2019, BS EN 61000-3-3:2013/A2:2021

### Test Procedure Used:

IEC 61000-4-2:2008, IEC 61000-4-3:2020, IEC 61000-4-4:2012,  
IEC 61000-4-5:2014/AMD1:2017, IEC 61000-4-6:2013, IEC 61000-4-8:2009, IEC 61000-4-  
11:2020

### We Declare:

The equipment described above is tested and assessed by Tianjin Dongdian Testing Service Co., Ltd. and in the configuration assessed the equipment complied with the standards specified above. The tested and assessed results are contained in this test report and Tianjin Dongdian Testing Service Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these assessments.

**After test and evaluation, our opinion is that the equipment in accordance with above standards.**

Report No.:	DDT-B22081804-1E01		
Date of Receipt:	Aug. 19, 2022	Date of Test:	Aug. 21, 2022 ~ Sep. 05, 2022



Prepared By:

*May Zhang*

May Zhang/Engineer

Approved By:

*Aaron Zhang*

Aaron Zhang/EMC Manager

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